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# **Pattern Recognition and Applications**

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Deadline for manuscript submissions:

closed (31 October 2021)

### **Message from the Guest Editor**

In this Special Issue, we look for new contributions, especially, but not limited, to new research fields where pattern recognition methods are relatively new. The approach can be a traditional one, based on the extraction of some features using parametric or non-parametric methods, or using deep learning techniques exploiting the availability of a large amount of data or transfer learning.

A few of the popular applications this Special Issue will make reference to include computer vision, speech signals, energy industry, and biomedical applications. Keywords are as follows:

- Pattern recognition
- Machine learning
- Deep learning
- Big data
- Classification
- Detection
- Signal Processing
- Artificial Intelligence
- Computer Science
- Computer vision
- Biomedicine











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### **Editor-in-Chief**

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## **Message from the Editor-in-Chief**

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